

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination SHIN ET AL.	
			Examiner Phillip Nguyen	Art Unit 2828	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,381,047	04-2002	Frigo et al.	398/79
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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